Application/Control No. Applicant(s)/Patent Under Reexamination 10/601,860 HAN, SUK-GYUN Notice of References Cited Examiner Art Unit Page 1 of 1 Edgardo San Martin 2837 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-Α US-В С US-D US-Ε US-F US-US-G US-Н USı J US-K US-US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν JP 08317696 A 11-1996 Japan TANAKA, MAKOTO H02P 08/14 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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